



4/20/2008

RELIABILITY MONITOR REPORT  
FOR

**SVL 0.6 $\mu$ m Silicon Gate CMOS**

**MAXIM Integrated Products**

120 San Gabriel Dr.  
Sunnyvale, CA 94086

This Report was prepared by  
Maxim Reliability Engineering

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX9776ETJ+	MAX9789AETJ+
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The calculated failure rate for devices using this process is:

**FAILURE RATE:**                      **MTTF (YRS): 48639**                      **FITS: 2.3**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%**                      **Ea: 0.7**                      **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2007 and 3/31/2008 .

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**Process Information:**

Process Description:                      SVL 0.6µm Silicon Gate CMOS

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE		MAX9789AETJ+	135C, 5.25V	1000 HRS	77	0	
			135C, 5.25V	1000 HRS	78	0	
		MAX9776ETJ+	135C, 5.25V	1000 HRS	48	0	
			135C, 5.25V	1000 HRS	48	0	
<b>Total:</b>						<b>0</b>	

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